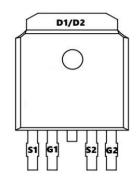
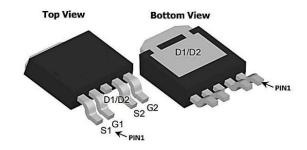


# 30V N+P-Channel Enhancement Mode MOSFET

## **Description**

The SX30G03GD uses advanced trench technology to provide excellent RDS(ON), low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.





#### **General Features**

V<sub>DS</sub> = 30V I<sub>D</sub> =38A

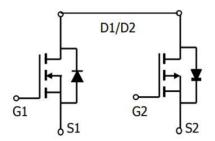
 $R_{DS(ON)} < 12m\Omega$  @  $V_{GS}=10V$ 

 $V_{DS} = -30V I_{D} = -35A$ 

 $R_{DS(ON)} < 20m\Omega$  @  $V_{GS}$ =-10V

## **Application**

**BLDC** 



Absolute Maximum Ratings (T<sub>c</sub>=25°Cunless otherwise noted)

Symbol	Parameter	N-Ch	P-Ch	Units
Vos	Drain-Source Voltage	30	-30	V
Vgs	Gate-Source Voltage	±20	±20	V
lo@Ta=25℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	38	-35	А
lo@Ta=70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	21	-18.1	А
Ірм	Pulsed Drain Current <sup>2</sup>	90	-85	Α
EAS	Single Pulse Avalanche Energy <sup>3</sup>	22	22	mJ
las	Avalanche Current	28	23	Α
PD@TA=25°C	Total Power Dissipation <sup>4</sup>	46	46	W
Тѕтс	Storage Temperature Range	-55 to 150		$^{\circ}\!\mathbb{C}$
TJ	Operating Junction Temperature Range	-55 to 150		°C
Reja	Thermal Resistance Junction-Ambient <sup>1</sup>	62.5		°C/W
Rejc	Thermal Resistance Junction-Case <sup>1</sup>	6.0		°C/W



## 30V N+P-Channel Enhancement Mode MOSFET

N-Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	Vgs=0V , Ip=250uA	30	33		V
∆BVDSS/∆T J	BVDSS Temperature Coefficient	Reference to 25℃ , I <sub>D</sub> =1mA		0.0193		V/°C
DDC(ON)	Static Prain Source On Registence?	V <sub>G</sub> s=10V , I <sub>D</sub> =30A	8	8.0	12	
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	Vgs=4.5V , Ip=15A		11	16	mΩ
VGS(th)	Gate Threshold Voltage	V V 1 050 A	1.2	1.6	2.5	V
$\triangle V$ GS(th)	V <sub>GS(th)</sub> Temperature Coefficient	Vgs=Vps , Ip =250uA		-3.97		mV/℃
IDOO	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	
IDSS		V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	uA
IGSS	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =30A		34		S
Rg	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		1.8		Ω
$Q_g$	Total Gate Charge (4.5V)			9.8		
Qgs	Gate-Source Charge	V <sub>DS</sub> =15V , V <sub>GS</sub> =4.5V , I <sub>D</sub> =15A		4.2		nC
$Q_{gd}$	Gate-Drain Charge			3.6		
Td(on)	Turn-On Delay Time			4		
Tr	Rise Time	V <sub>DD</sub> =15V , V <sub>GS</sub> =10V , R <sub>G</sub> =3.3Ω		8		
Td(off)	Turn-Off Delay Time	lo=15A		31		ns
Tf	Fall Time			4		
Ciss	Input Capacitance			940		
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		131		pF
Crss	Reverse Transfer Capacitance			109		
ls	Continuous Source Current <sup>1,5</sup>	\/\/0\/			43	Α
ISM	Pulsed Source Current <sup>2,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			112	Α
VSD	Diode Forward Voltage <sup>2</sup>	Vgs=0V , Is=1A , Tյ=25℃			1	V
trr	Reverse Recovery Time	IF=30A , dI/dt=100A/μs ,		8.5		nS
Qrr	Reverse Recovery Charge	TJ=25°C		2.2		nC

#### Note:

- 1、The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width  $\leq 300 us$  , duty cycle  $\leq 2\%$
- 3、The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1Mh,IAS=28A
- 5. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

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## 30V N+P-Channel Enhancement Mode MOSFET

#### P-Channel Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

	2.00th 10th 0 har a 0to 110th 10th (15 20 0	, 4111000 041101 11100 1				
Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	Vgs=0V, In= -250µA	-30	-33	-	V
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -30V, V <sub>GS</sub> =0V,	-	-	-1	μΑ
IGSS	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = -250µA	-1.2	-1.5	-2.5	V
DDC(an)		Vgs= -10V, Ip= -10A -	16	20	_	
RDS(on)	Static Drain-Source on-Resistance note3	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -5A	-	25	30	mΩ
Ciss	Input Capacitance		-	1250	-	pF
Coss	Output Capacitance	V <sub>DS</sub> = -15V, V <sub>GS</sub> =0V,	-	327	-	pF
Crss	Reverse Transfer Capacitance	1-1.0MHZ	_	278	_	pF
Qg	Total Gate Charge	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -5A  V <sub>DS</sub> = -15V, V <sub>GS</sub> =0V, f=1.0MHz  V <sub>DS</sub> = -15V, I <sub>D</sub> = -9.1A, V <sub>GS</sub> = -10V	-	30	-	nC
Qgs	Gate-Source Charge		-	5.3	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge	Vgs= -10V	_	7.6	_	nC
td(on)	Turn-on Delay Time		-	14	-	ns
tr	Turn-on Rise Time	VDD= -15V, ID= -6A,	-	20	-	ns
td(off)	Turn-off Delay Time	Vgs= -10V, Rgen= $2.5\Omega$	-	95	-	ns
tf	Turn-off Fall Time		-	65	-	ns
IS	Maximum Continuous Drain to Source Dioc	de Forward Current	-	-	-10	Α
ISM	Maximum Pulsed Drain to Source Did	ode Forward Current	-	-	-40	Α
VSD	Drain to Source Diode Forward Voltage	Vgs=0V, Is= -11A	-	-0.8	-1.2	V

#### Note

- 1 . The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2 . The data tested by pulsed , pulse width  $\leq 300 \text{us}$  , duty cycle  $\leq 2\%$
- $3\$  The EAS data shows Max. rating . The test condition is VDD=-25V,VGS=-10V,L=0.1mH,IAS=-23A
- 4 . The power dissipation is limited by 150 ℃ junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.





# **N-Typical Characteristics**

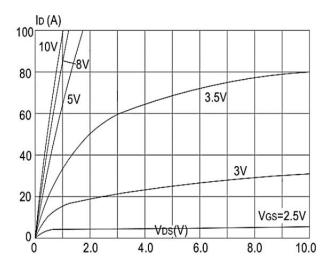


Figure1: Output Characteristics

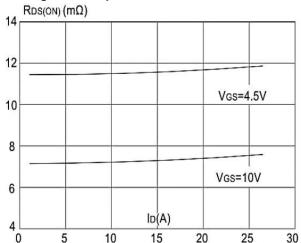


Figure 3:On-resistance vs. Drain Current

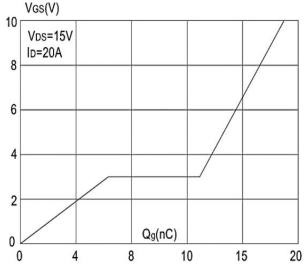
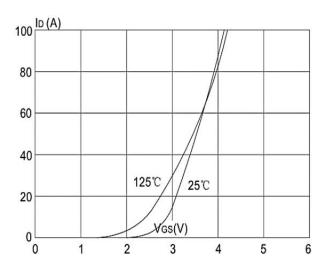


Figure 5: Gate Charge Characteristics



30V N+P-Channel Enhancement Mode MOSFET

Figure 2: Typical Transfer Characteristics

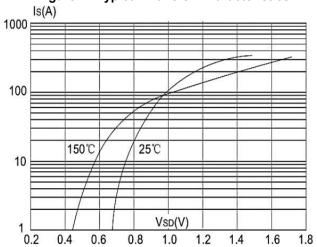


Figure 4: Body Diode Characteristics

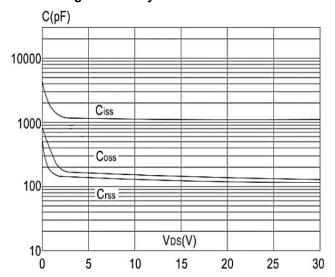


Figure 6: Capacitance Characteristics



## **N-Typical Characteristics**

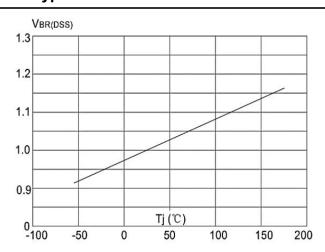


Figure 7: Normalized Breakdown Voltage vs Junction Temperature

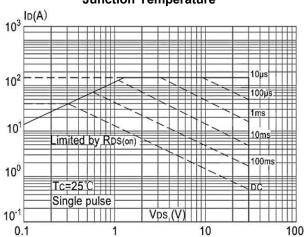


Figure 9: Maximum Safe Operating Area
Temperature

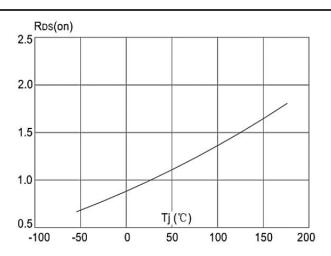


Figure 8: Normalized on Resistance vs.

Junction Temperature

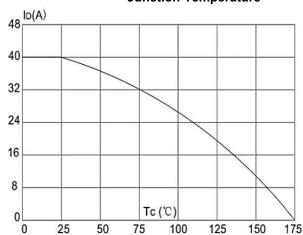


Figure 10: Maximum Continuous Drain Current vs. Ambient

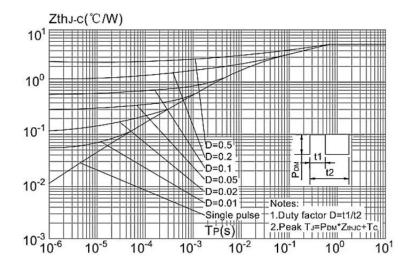
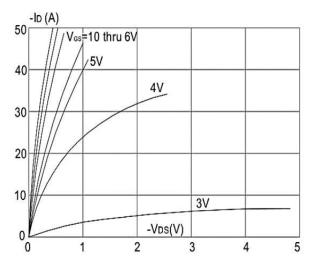
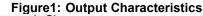


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien



#### **P-Channel Typical Characteristics**





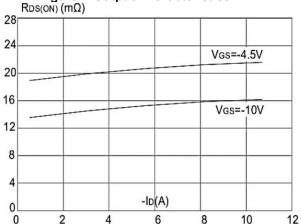


Figure 3:On-resistance vs. Drain Current

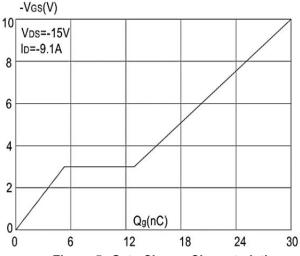


Figure 5: Gate Charge Characteristics

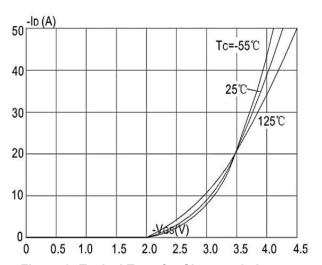


Figure 2: Typical Transfer Characteristics

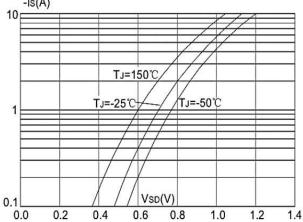
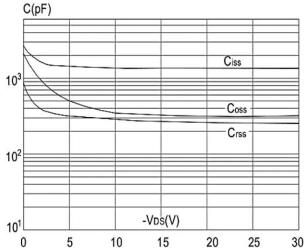


Figure 4: Body Diode Characteristics



**Figure 6: Capacitance Characteristics** 



#### **P-Channel Typical Characteristics**

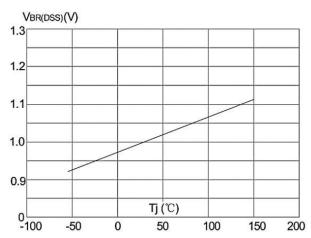


Figure 7: Normalized Breakdown Voltage vs.
Junction Temperature

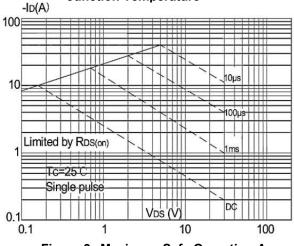


Figure 9: Maximum Safe Operating Area

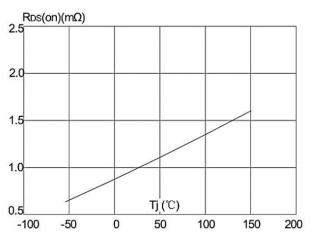


Figure 8: Normalized on Resistance vs. Junction Temperature

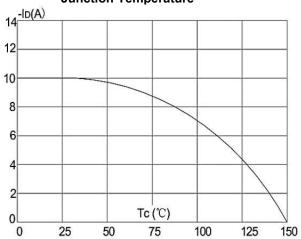


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

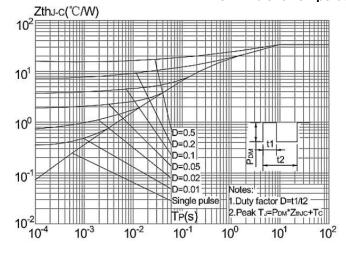


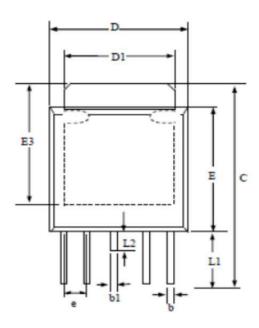
Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

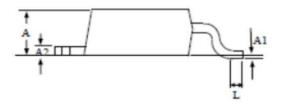
7





# Package Mechanical Data:TO-252-4L





SYMBOLS	Millimeters			
311.2023	MIN	NOM	MAX	
D	6.30	6.55	6.80	
D1	4.80	5.35	5.90	
С	9.30	9.75	10.20	
Е	5.30	5.80	6.30	
E3	4.50	5.15	5.80	
L	0.90	1.35	1.80	
Ll	2.00	2.53	3.05	
L2	0.50	0.85	1.20	
ь	0.30	0.50	0.70	
bl	0.40	0.60	0.80	
A	2.10	2.30	2.50	
A2	0.40	0.53	0.65	
A1	0.00	0.10	0.20	
6	1.20	1.30	1.40	

- 1.All Dimensions Are in Millimeters.
- 2. Dimension Does Not Include Mold Protrusions.

**Package Marking and Ordering Information** 

Product ID	Pack	Marking	Qty(PCS)
TAPING	TO-252-4L		2500

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